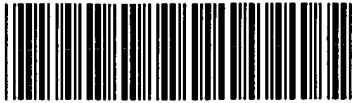


**Search Notes**

Application/Control No.

10/074,616

Examiner

Marc R. Filipczyk

Applicant(s)/Patent under  
Reexamination

GAI ET AL.

Art Unit

2163

**SEARCHED**

Class	Subclass	Date	Examiner
707	1-4, 6, 100, 101	3/1/2007	MF
update	search	3/2/2007	MF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
707	6	3/1/2007	MF
707	1, 3	3/1/2007	MF

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST; Class 707 search; match token, substring, action, task, parallel, pattern, CAM, segment; consulted AI. Kindrer (AU2163)	3/1/2007	MF
EAST, IEEE, CiteSeer; pattern, border, CAM	3/2/2007	MF